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Application/Control No.	Applicant(s)/Patent under Reexamination					
10/707,339	SHIH ET AL.					
Examiner	Art Unit					
Don Williams	2878					

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Class	Subclass	Date	Examiner
250	221	2/23/2006	DW
	222.1	2/23/2006	DW
345	163	2/23/2006	DW
	165	2/23/2006	DW
	166	2/23/2006	DW
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INI	ERFERENC	Date Examiner						
Class	Subclass	Date	Examiner					
250	221	2/23/2006	DW					
345	166	2/23/2006	DW					

SEARCH NOT (INCLUDING SEARCH		)
	DATE	EXMR
East,BRS: US-PGPUB, USPAT, USOCR, EPO, JPO, DERWENT, IBM_TDB	2/23/2006	DW
Consulted with Examiner Than of AU 2878.	2/23/2006	DW
Consulted with Examiner Eisen of AU 2674.	2/23/2006	DW
Consulted with Examiner Allen of AU 2878.	2/23/2006	DW